

LM6172 デュアル、高速、低消費電力、低歪み、電圧帰還型アンプ

1 特長

- 特に記述のない限り標準値
- 使いやすい電圧帰還トポロジ
- 高いスルーレート: 3000V/μs
- 広いユニティゲイン帯域幅: 100 MHz
- 低い消費電流: 2.3mA/チャンネル
- 大出力電流: 50mA/チャンネル
- 規定動作: ±15V および ±5V

2 アプリケーション

- スキャナの I/V (電流 / 電圧) コンバータ
- ADSL/HDSL ドライバ
- マルチメディア放送システム
- ビデオ アンプ
- NTSC、PAL、SECAM システム
- ADC/DAC バッファ
- パルス アンプおよびピーク検出器

3 概要

LM6172 は、デュアル高速電圧帰還型アンプです。このデバイスはユニティゲイン安定で、優れた DC および AC 性能を備えています。LM6172 は、100MHz のユニティゲイン帯域幅、3000V/μs のスルーレート、チャンネルあたりの出力電流 50mA で、デュアル アンプで高性能を実現し、さらに、チャンネルあたりの消費電流はわずか 2.3mA です。

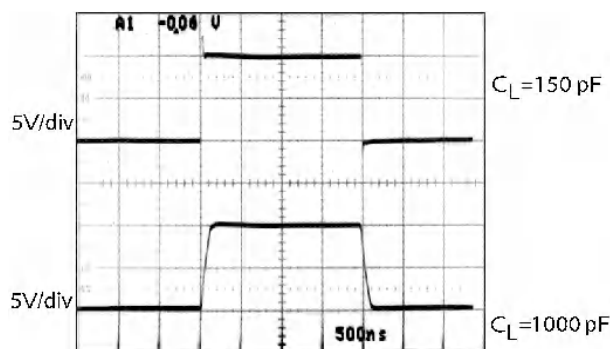
LM6172 は、ADSL、スキャナ、超音波機器など、大きい電圧振幅を必要とするシステム向けに ±15V の電源で動作します。このデバイスは、携帯型ビデオ システムなどの低電圧アプリケーション向けの ±5V 電源についても仕様が規定されています。

LM6172 は、テキサス・インスツルメンツの先進的な相補型バイポーラ プロセスで製造されます。これらと同じ特長を持つシングル アンプについては、[LM6171 データシート](#)を参照してください。

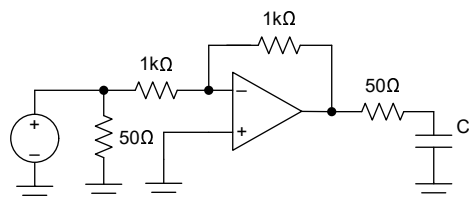
パッケージ情報

部品番号	パッケージ ⁽¹⁾	パッケージサイズ ⁽²⁾
LM6172	D (SOIC, 8)	4.9mm × 6mm
	P (PDIP, 8)	9.81mm × 9.43mm

- (1) 詳細については、[セクション 10](#)を参照してください。
- (2) パッケージサイズ (長さ × 幅) は公称値であり、該当する場合はピンも含まれます。



LM6172 による容量性負荷の駆動



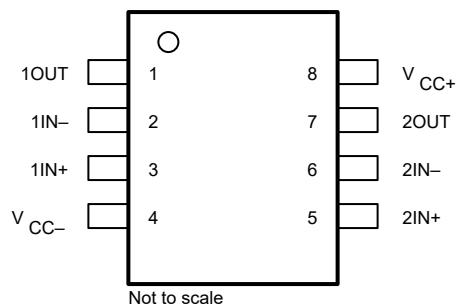
LM6172 による容量性負荷の駆動



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4 Pin Configuration and Functions



**図 4-1. D Package, 8-Pin SOIC
and P Package, 8-Pin PDIP
(Top View)**

表 4-1. Pin Functions

PIN		TYPE	DESCRIPTION
NAME	NO.		
1IN-	2	Input	Channel 1 inverting input
1IN+	3	Input	Channel 1 noninverting input
1OUT	1	Output	Channel 1 output
2IN-	6	Input	Channel 2 inverting input
2IN+	5	Input	Channel 2 noninverting input
2OUT	7	Output	Channel 2 output
V _{CC-}	4	—	Negative power supply
V _{CC+}	8	—	Positive power supply

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾ ⁽²⁾

		MIN	MAX	UNIT
V _S	Supply voltage (V _{CC+} – V _{CC-})		36	V
V _I	Differential input voltage		±10	V
V _{CM}	Common-mode voltage	V _{CC-} – 0.3	V _{CC+} + 0.3	V
I _{IN}	Input current		±10	mA
I _{SC}	Output current short to ground ⁽³⁾		Continuous	A
T _J	Junction temperature ⁽⁴⁾		150	°C
T _{stg}	Storage temperature	–65	150	°C
T _{SOLDER}	Infrared or convection reflow (20 seconds)		235	°C
	Wave soldering lead temp (10 seconds)		260	

- (1) If Military/Aerospace specified devices are required, please contact the Texas Instruments Sales Office/Distributors for availability and specifications.
- (2) Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (3) Continuous short circuit operation at elevated ambient temperature can result in exceeding the maximum allowed junction temperature of 150°C.
- (4) The maximum power dissipation is a function of T_{J(MAX)}, R_{θJA}, and T_A. The maximum allowable power dissipation at any ambient temperature is P_D = (T_{J(MAX)} – T_A) / R_{θJA}. All numbers apply for packages soldered directly into a PC board.

5.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±3000	V
		Machine model ⁽²⁾	±300	V

- (1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.
- (2) Machine model, 200Ω in series with 100pF.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	TYP	MAX	UNIT
V _S	Supply voltage	5.5		36	
T _A	Ambient temperature	–40		85	°C

5.4 Thermal Information

THERMAL METRIC ⁽¹⁾		LM6172		UNIT
		D (SOIC)	P (PDIP)	
		8 PINS	8 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	172	108	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	62.4	52.4	°C/W
R _{θJB}	Junction-to-board thermal resistance	55.7	51.9	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	16.5	6.8	°C/W
Ψ _{JB}	Junction-to-board characterization parameter	55.1	51.1	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

- (1) For information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

5.5 Electrical Characteristics $\pm 15V$

at $T_J = 25^\circ\text{C}$, $V_{CC+} = 15V$, $V_{CC-} = -15V$, $V_{CM} = 0V$, and $R_L = 1k\Omega$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN ⁽²⁾	TYP ⁽¹⁾	MAX ⁽²⁾	UNIT
V_{OS}	Input offset voltage				0.4	3	mV
		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$				4	
TCV_{OS}	Input offset voltage average drift				6		$\mu\text{V}/^\circ\text{C}$
I_B	Input bias current				1.2	3	μA
		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$				4	
I_{OS}	Input offset current				0.02	2	μA
		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$				3	
R_{IN}	Input resistance	Common-mode			40		$M\Omega$
		Differential-mode			4.9		
R_O	Open-loop output resistance				14		Ω
$CMRR$	Common-mode rejection ratio	$V_{CM} = \pm 10V$		70	110		dB
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	65			
$PSRR$	Power supply rejection ratio	$V_S = \pm 15V$ to $\pm 5V$		75	95		dB
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	70			
V_{CM}	Input common-mode voltage	$CMRR > 60\text{dB}$			± 13.5		V
A_V	Large-signal voltage gain ⁽³⁾	$R_L = 1k\Omega$, $V_{OUT} = \pm 5V$		80	86		dB
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	75			
		$R_L = 100\Omega$, $V_{OUT} = \pm 5V$		65	78		
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	60			
V_O	Output swing	$R_L = 1k\Omega$, sourcing		12.5	13.2		V
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	12			
		$R_L = 1k\Omega$, sinking			-13.1	-12.5	
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$			-12	
		$R_L = 100\Omega$, sourcing		6	9		
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	5			
		$R_L = 100\Omega$, sinking			-8.5	-6	
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$			-5	
	Continuous output current (open loop) ⁽⁴⁾	Sourcing, $R_L = 100\Omega$		60	90		mA
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	50			
		Sinking, $R_L = 100\Omega$			-85	-60	
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$			-50	
I_{SC}	Output short-circuit current	D package	Sourcing		173		mA
			Sinking		-183		
		P package	Sourcing		107		
			Sinking		-105		
I_S	Supply current				4.6	8	mA
		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$				9	
SR	Slew rate ⁽⁵⁾	$A_V = +2$, $V_{IN} = 13V_{PP}$			3000		V/ μs
		$A_V = +2$, $V_{IN} = 10V_{PP}$			2500		
	Unity-gain bandwidth	D package			80		MHz
		P package			100		
	-3dB frequency	$A_V = +1$			160		MHz
		$A_V = +2$			62		MHz

5.5 Electrical Characteristics $\pm 15V$ (続き)

at $T_J = 25^\circ\text{C}$, $V_{CC+} = 15V$, $V_{CC-} = -15V$, $V_{CM} = 0V$, and $R_L = 1k\Omega$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN ⁽²⁾	TYP ⁽¹⁾	MAX ⁽²⁾	UNIT
ϕ_m	Phase margin				40		Deg
	Bandwidth matching between channels				2		MHz
t_s	Settling time (0.1%)	$A_V = -1$, $V_{OUT} = \pm 5V$, $R_L = 500\Omega$			65		ns
A_D	Differential gain ⁽⁶⁾				0.28		%
ϕ_D	Differential phase ⁽⁶⁾				0.6		°
e_n	Input-referred voltage noise	$f = 10\text{kHz}$			12		nV/ $\sqrt{\text{Hz}}$
i_n	Input-referred current noise	$f = 10\text{kHz}$			1		pA/ $\sqrt{\text{Hz}}$
HD2	Second harmonic distortion	D package	$f_{IN} = 10\text{kHz}$		-88		dBc
			$f_{IN} = 5\text{MHz}$		-50		
		P package	$f_{IN} = 10\text{kHz}$		-110		
			$f_{IN} = 5\text{MHz}$		-50		
HD3	Third harmonic distortion	D package	$f_{IN} = 10\text{kHz}$		-93		dBc
			$f_{IN} = 5\text{MHz}$		-41		
		P package	$f_{IN} = 10\text{kHz}$		-105		
			$f_{IN} = 5\text{MHz}$		-50		

(1) Typical values represent the most likely parametric norm.

(2) All limits are specified by testing or statistical analysis.

(3) Large-signal voltage gain is the total output swing divided by the input signal required to produce that swing. For $V_S = \pm 15V$, $V_{OUT} = \pm 5V$. For $V_S = 5V$, $V_{OUT} = \pm 1V$.

(4) The open-loop output current is the output swing with the 100Ω load resistor divided by that resistor.

(5) Slew rate is the average of the rising and falling slew rates.

(6) Differential gain and phase are measured with $A_V = +2$, $V_{IN} = 1V_{PP}$ at 3.58MHz and both input and output 75Ω terminated.

5.6 Electrical Characteristics ±5V

at $T_J = 25^\circ\text{C}$, $V_{CC+} = 5\text{V}$, $V_{CC-} = -5\text{V}$, $V_{CM} = 0\text{V}$, and $R_L = 1\text{k}\Omega$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN ⁽²⁾	TYP ⁽¹⁾	MAX ⁽²⁾	UNIT
V_{OS}	Input offset voltage				0.1	3	mV
		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$				4	
TCV_{OS}	Input offset voltage average drift				4		$\mu\text{V}/^\circ\text{C}$
I_B	Input bias current				1.4	2.5	μA
		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$				3.5	
I_{OS}	Input offset current				0.02	1.5	μA
		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$				2.2	
R_{IN}	Input resistance	Common-mode			40		$\text{M}\Omega$
		Differential-mode			4.9		
R_O	Open loop output resistance				14		Ω
$CMRR$	Common-mode rejection ratio	$V_{CM} = \pm 2.5\text{V}$		70	105		dB
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	65			
$PSRR$	Power supply rejection ratio	$V_S = \pm 15\text{V}$ to $\pm 5\text{V}$		75	95		dB
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	70			
V_{CM}	Input common-mode voltage	$CMRR > 60\text{dB}$			± 3.7		V
A_V	Large-signal voltage gain ⁽³⁾	$R_L = 1\text{k}\Omega$, $V_{OUT} = \pm 1\text{V}$		70	82		dB
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	65			
		$R_L = 100\Omega$, $V_{OUT} = \pm 1\text{V}$		65	78		
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	60			
V_O	Output swing	$R_L = 1\text{k}\Omega$, sourcing		3.1	3.4		V
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	3			
		$R_L = 1\text{k}\Omega$, sinking			-3.3	-3.1	
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$			-3	
		$R_L = 100\Omega$, sourcing		2.5	2.9		
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	2.4			
		$R_L = 100\Omega$, sinking			-2.7	-2.4	
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$			-2.3	
				25	29		
			$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	24			
I_{SC}	Output short-circuit current	D package	Sourcing		155		mA
			Sinking		-158		
		P package	Sourcing		93		
			Sinking		-72		
I_S	Supply current				4.4	6	mA
		$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$				7	
SR	Slew rate ⁽⁵⁾	$A_V = +2$, $V_{IN} = 3.5V_{PP}$			750		V/ μs
	Unity-gain bandwidth				70		MHz
	-3dB frequency	$A_V = +1$			130		MHz
		$A_V = +2$	D package		75		
			P package		45		

5.6 Electrical Characteristics $\pm 5V$ (続き)

at $T_J = 25^\circ\text{C}$, $V_{CC+} = 5V$, $V_{CC-} = -5V$, $V_{CM} = 0V$, and $R_L = 1k\Omega$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN ⁽²⁾	TYP ⁽¹⁾	MAX ⁽²⁾	UNIT
ϕ_m	Phase margin	D Package			41		Deg
		P package			57		
t_s	Settling time (0.1%)	$A_V = -1$, $V_{OUT} = \pm 1V$, $R_L = 500\Omega$			72		ns
A_D	Differential gain ⁽⁶⁾				0.4		%
ϕ_D	Differential phase ⁽⁶⁾				0.7		°
e_n	Input-referred voltage noise	$f = 10\text{kHz}$			11		nV/ $\sqrt{\text{Hz}}$
i_n	Input-referred current noise	$f = 10\text{kHz}$			1		pA/ $\sqrt{\text{Hz}}$
HD2	Second harmonic distortion	D package	$f_{IN} = 10\text{kHz}$		-89		dBc
			$f_{IN} = 5\text{MHz}$		-48		
		P package	$f_{IN} = 10\text{kHz}$		-110		
			$f_{IN} = 5\text{MHz}$		-48		
HD3	Third harmonic distortion	D package	$f_{IN} = 10\text{kHz}$		-93		dBc
			$f_{IN} = 5\text{MHz}$		-42		
		P package	$f_{IN} = 10\text{kHz}$		-105		
			$f_{IN} = 5\text{MHz}$		-50		

(1) Typical values represent the most likely parametric norm.

(2) All limits are specified by testing or statistical analysis.

(3) Large-signal voltage gain is the total output swing divided by the input signal required to produce that swing. For $V_S = \pm 15V$, $V_{OUT} = \pm 5V$. For $V_S = 5V$, $V_{OUT} = \pm 1V$.

(4) The open-loop output current is the output swing with the 100Ω load resistor divided by that resistor.

(5) Slew rate is the average of the rising and falling slew rates.

(6) Differential gain and phase are measured with $A_V = +2$, $V_{IN} = 1V_{PP}$ at 3.58MHz and both input and output 75Ω terminated.

5.7 Typical Characteristics: D (SOIC, 8) Package

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

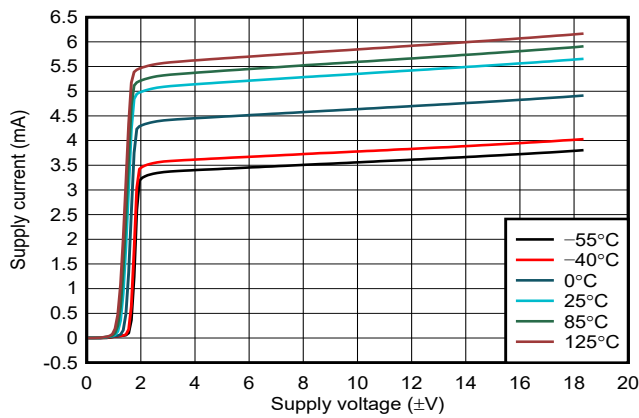


図 5-1. Supply Voltage vs Supply Current

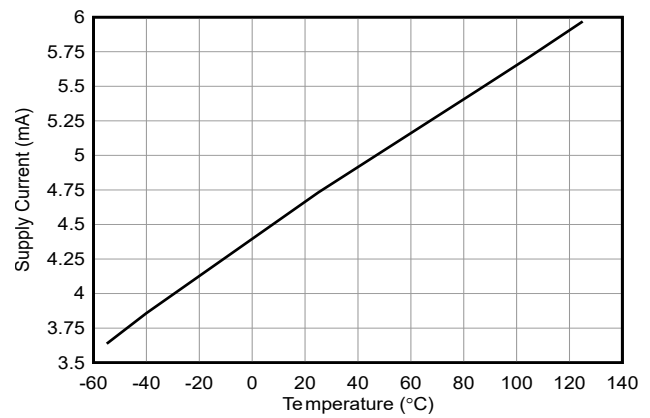


図 5-2. Supply Current vs Temperature

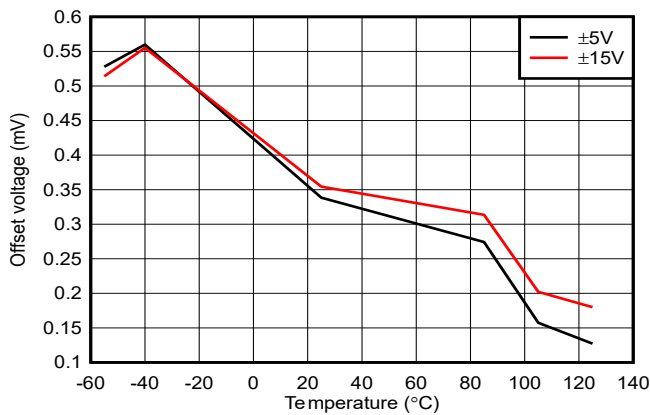


図 5-3. Input Offset Voltage vs Temperature

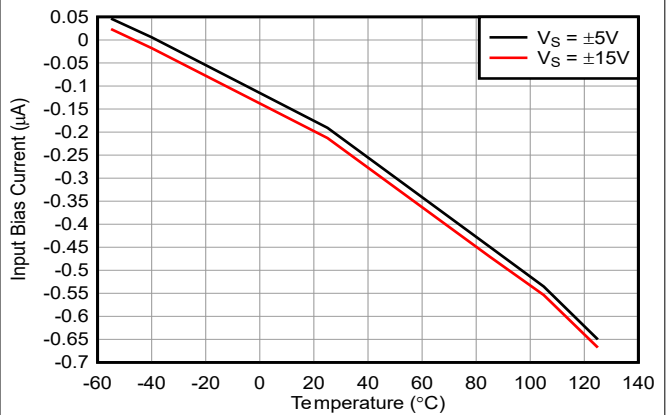


図 5-4. Input Bias Current vs Temperature

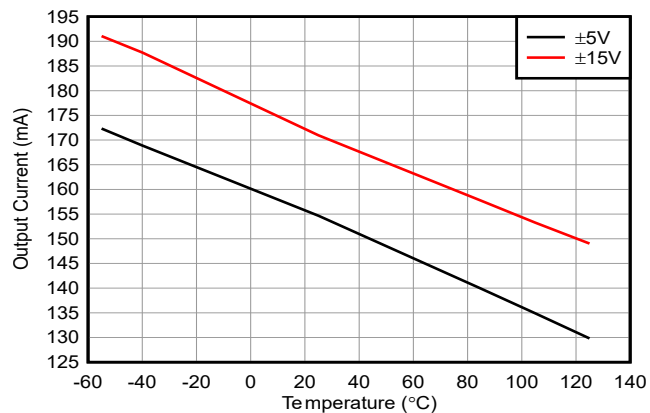


図 5-5. Short Circuit Current vs Temperature (Sourcing)

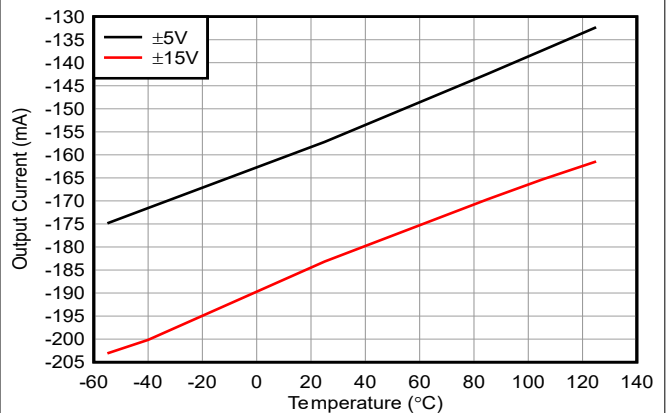


図 5-6. Short Circuit Current vs Temperature (Sinking)

5.7 Typical Characteristics: D (SOIC, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

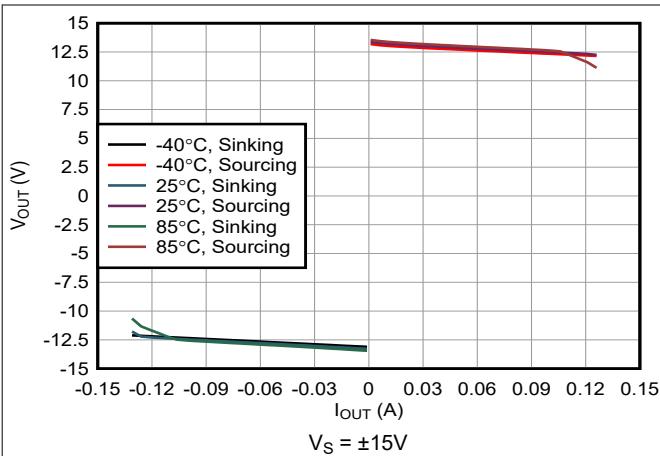


図 5-7. Output Voltage vs Output Current

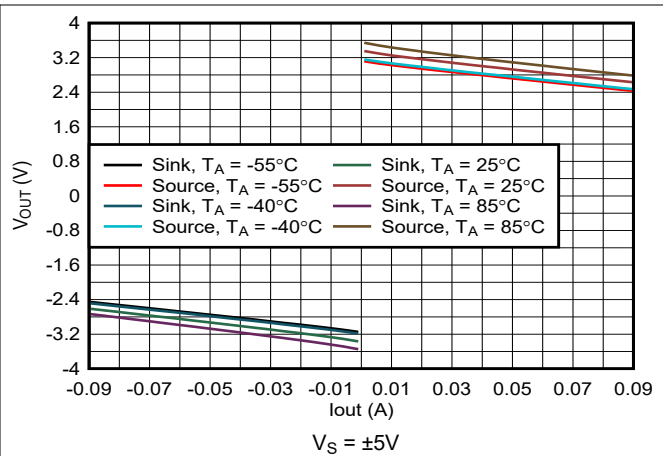


図 5-8. Output Voltage vs Output Current

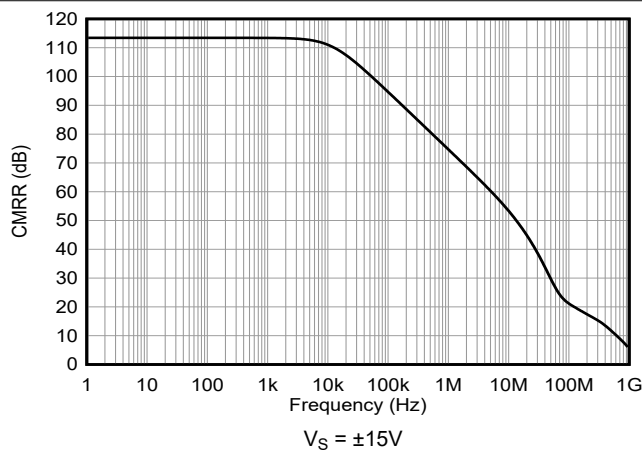


図 5-9. Common-Mode Rejection Ratio vs Frequency

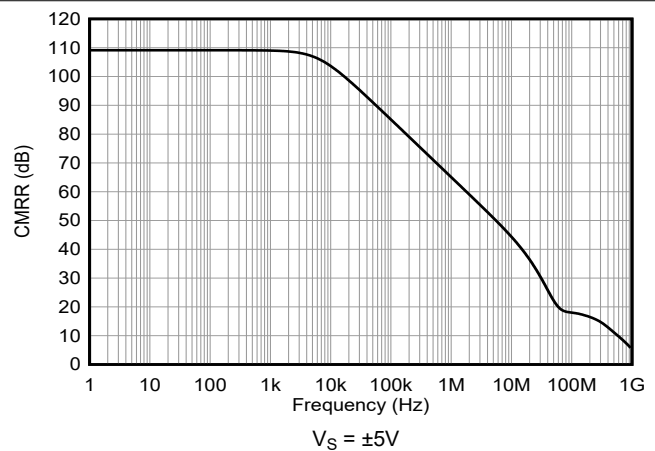


図 5-10. Common-Mode Rejection Ratio vs Frequency

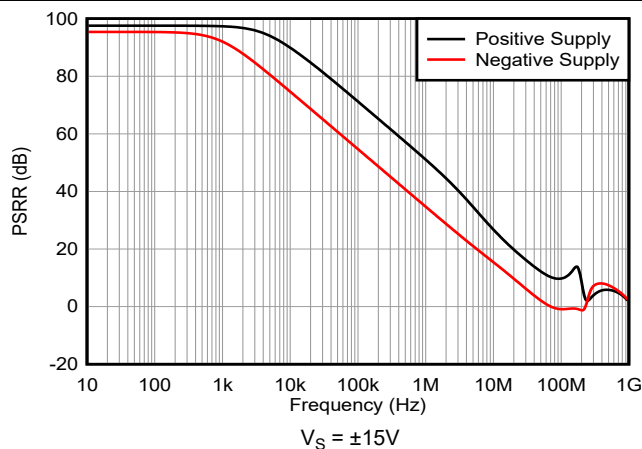


図 5-11. Power-Supply Rejection Ratio vs Frequency

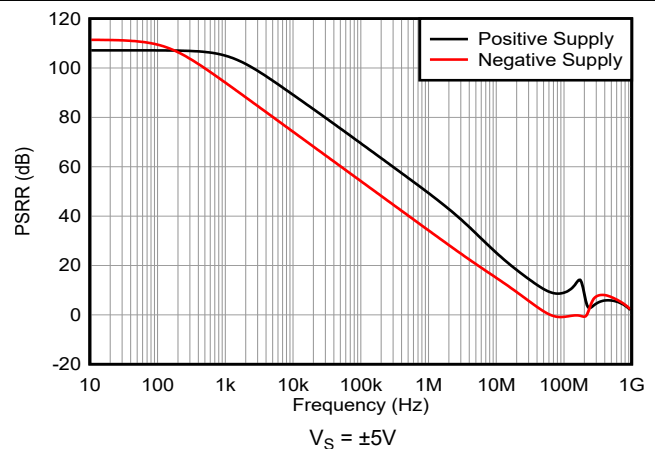


図 5-12. Power-Supply Rejection Ratio vs Frequency

5.7 Typical Characteristics: D (SOIC, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

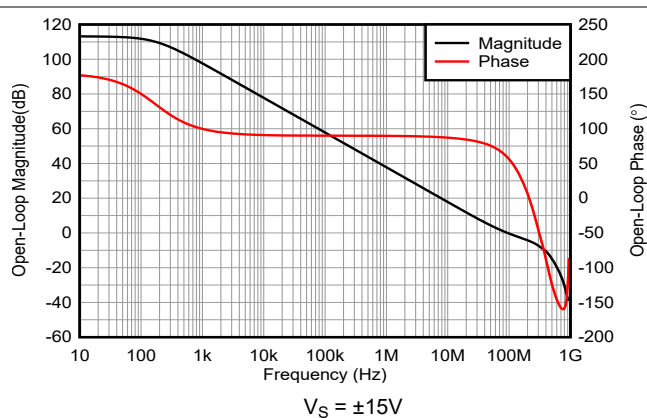


Figure 5-13. Open-Loop Frequency Response

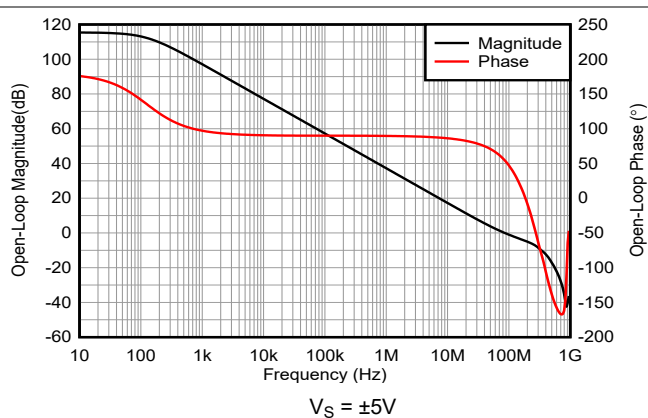


Figure 5-14. Open-Loop Frequency Response

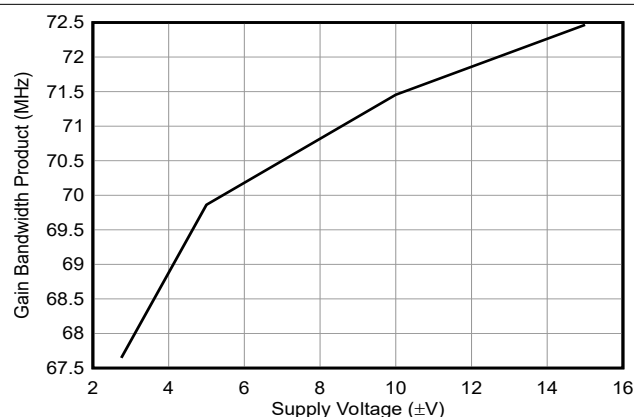


Figure 5-15. Gain-Bandwidth Product vs Supply Voltage at Different Temperature

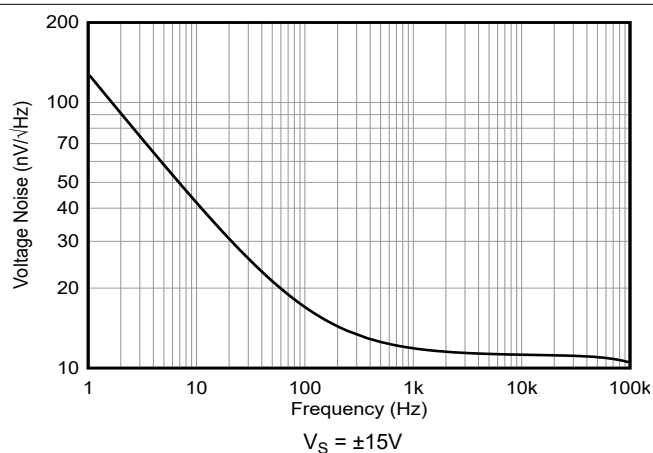


Figure 5-16. Input Voltage Noise vs Frequency

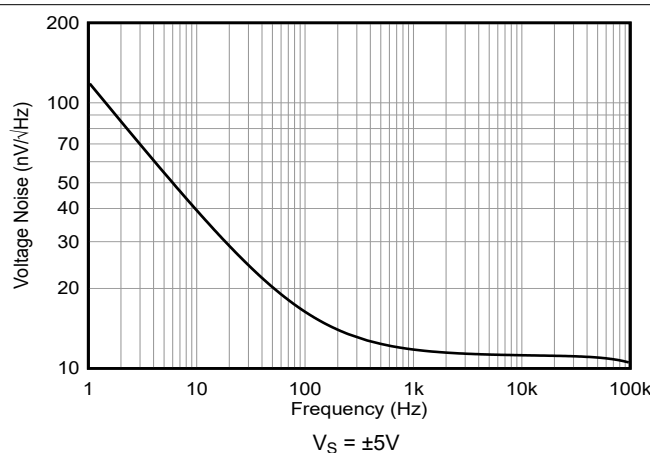


Figure 5-17. Input Voltage Noise vs Frequency

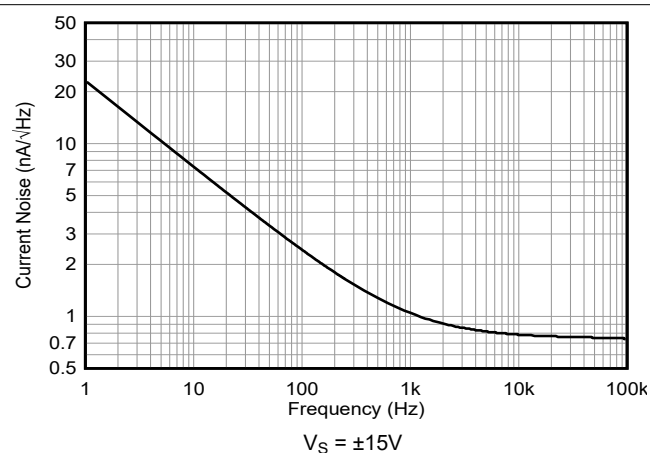


Figure 5-18. Input Current Noise vs Frequency

5.7 Typical Characteristics: D (SOIC, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

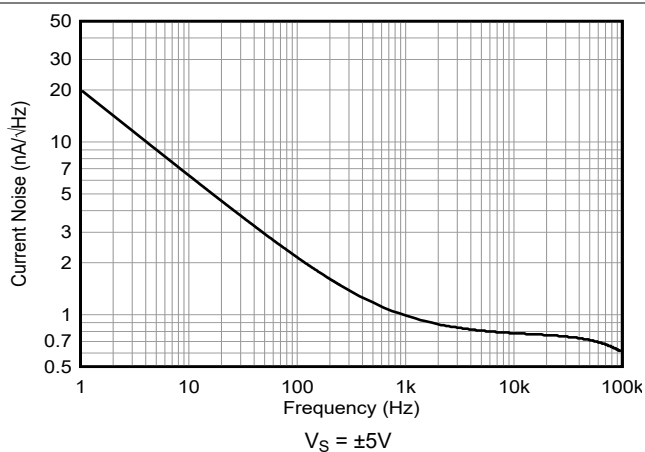


図 5-19. Input Current Noise vs Frequency

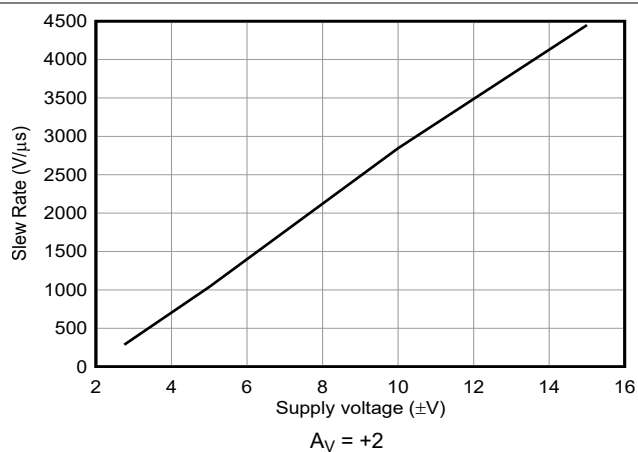


図 5-20. Slew Rate vs Supply Voltage

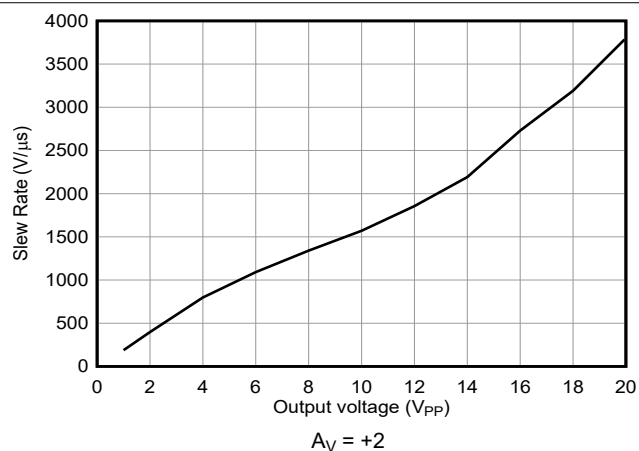


図 5-21. Slew Rate vs Output Voltage

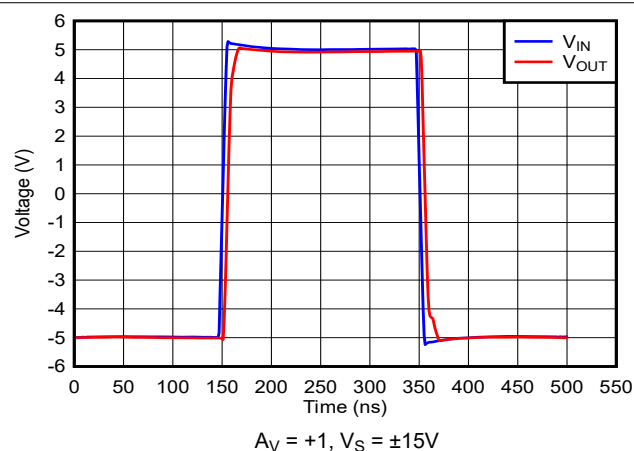


図 5-22. Large-Signal Pulse Response

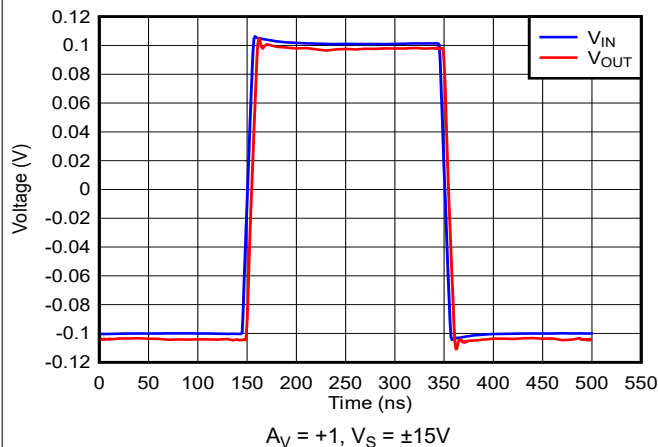


図 5-23. Small-Signal Pulse Response

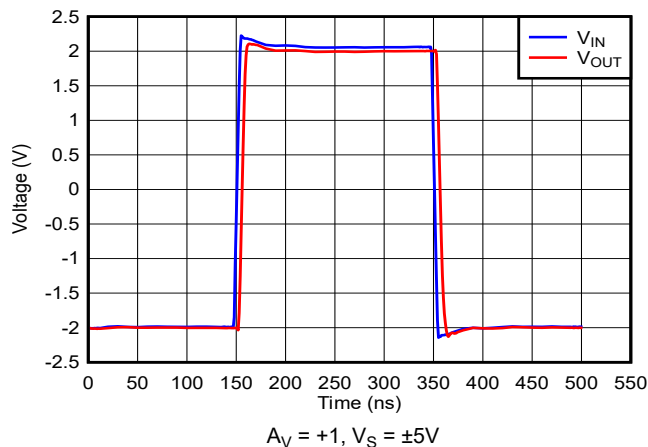


図 5-24. Large-Signal Pulse Response

5.7 Typical Characteristics: D (SOIC, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

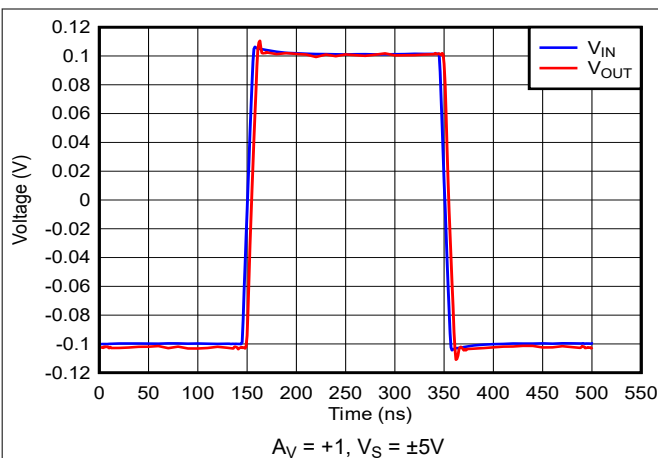


図 5-25. Small-Signal Pulse Response

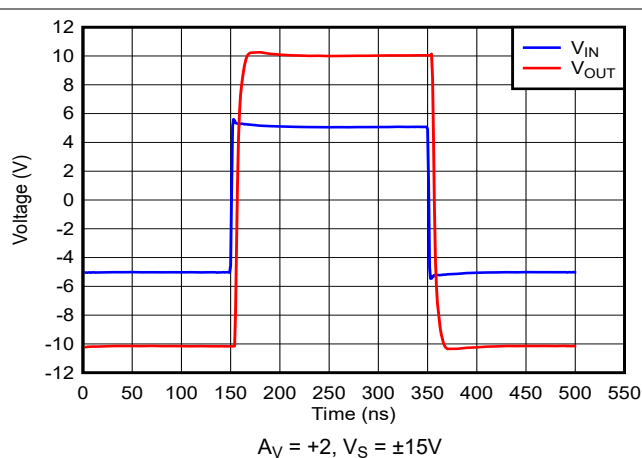


図 5-26. Large-Signal Pulse Response

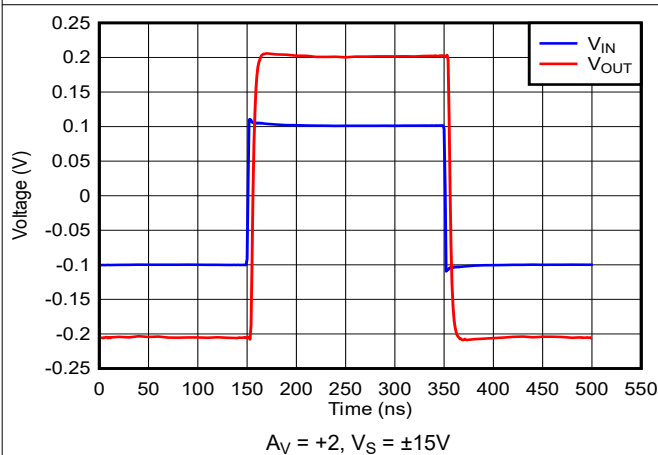


図 5-27. Small-Signal Pulse Response

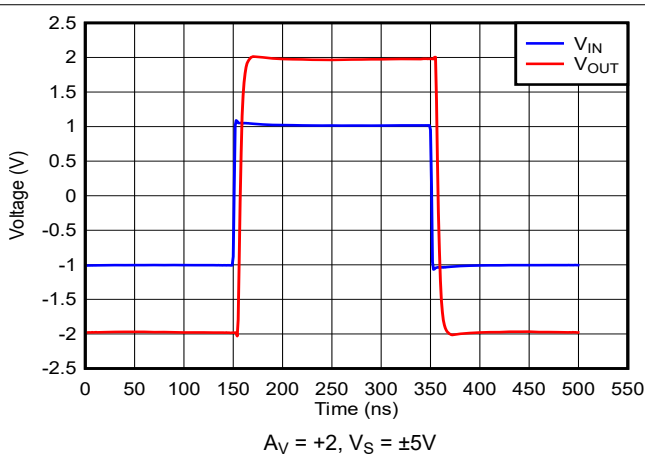


図 5-28. Large-Signal Pulse Response

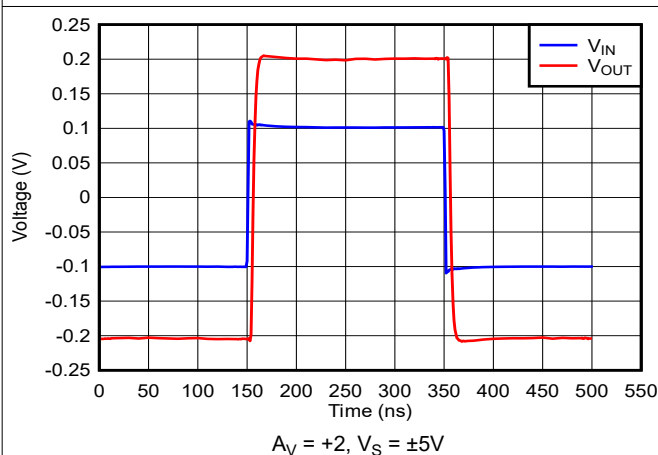


図 5-29. Small-Signal Pulse Response

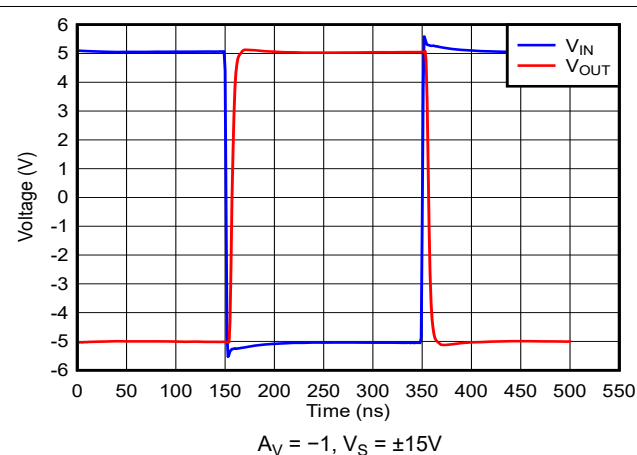


図 5-30. Large-Signal Pulse Response

5.7 Typical Characteristics: D (SOIC, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

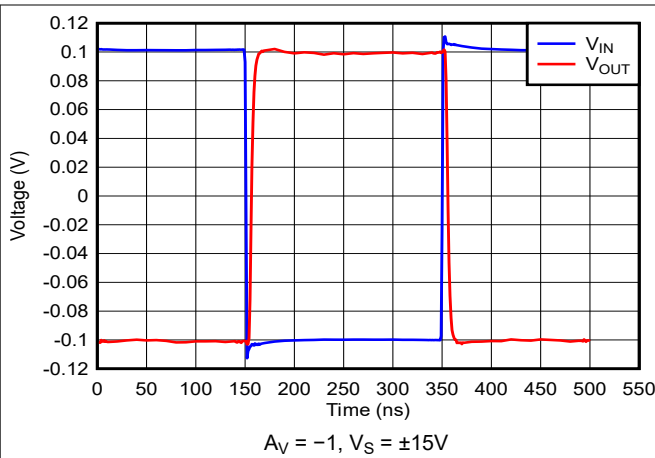


図 5-31. Small-Signal Pulse Response

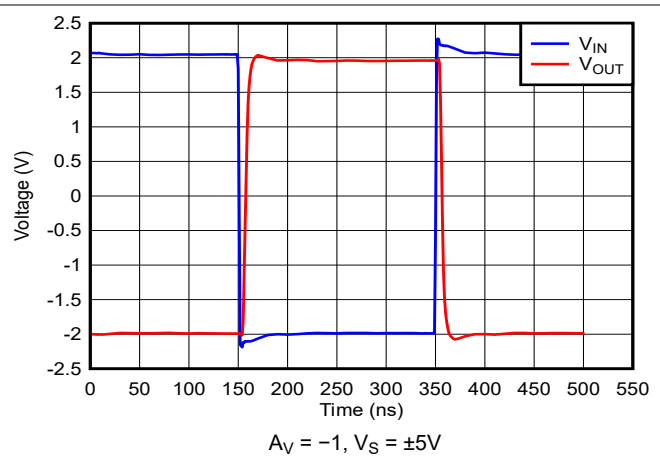


図 5-32. Large-Signal Pulse Response

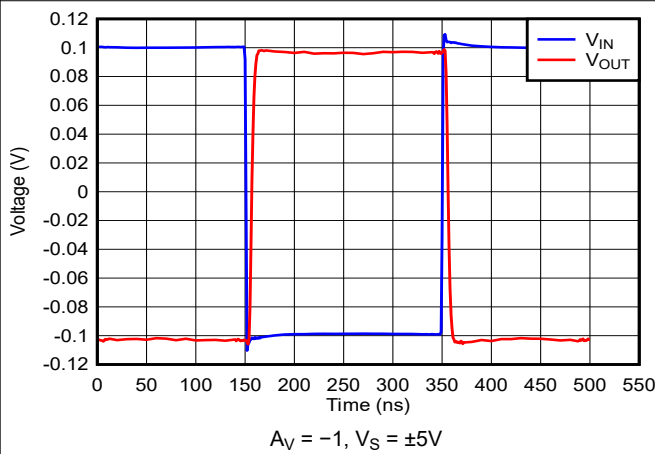


図 5-33. Small-Signal Pulse Response

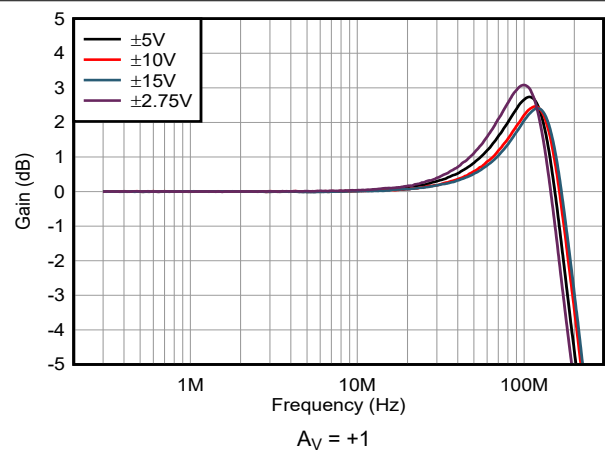


図 5-34. Closed-Loop Frequency Response vs Supply Voltage

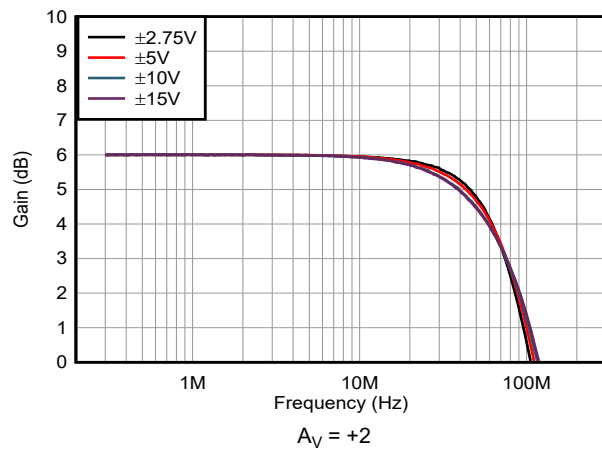


図 5-35. Closed-Loop Frequency Response vs Supply Voltage

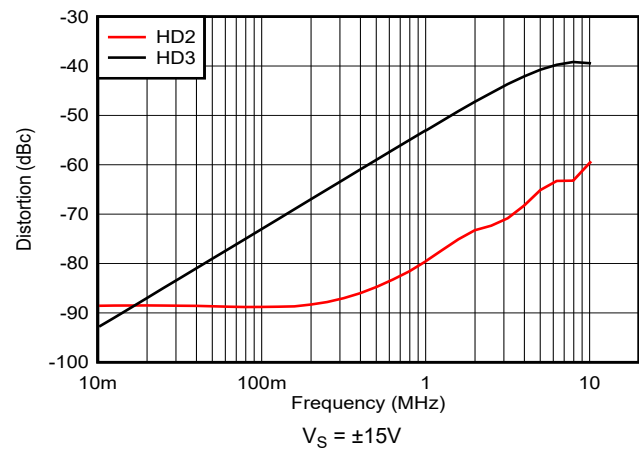


図 5-36. Harmonic Distortion vs Frequency

5.7 Typical Characteristics: D (SOIC, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

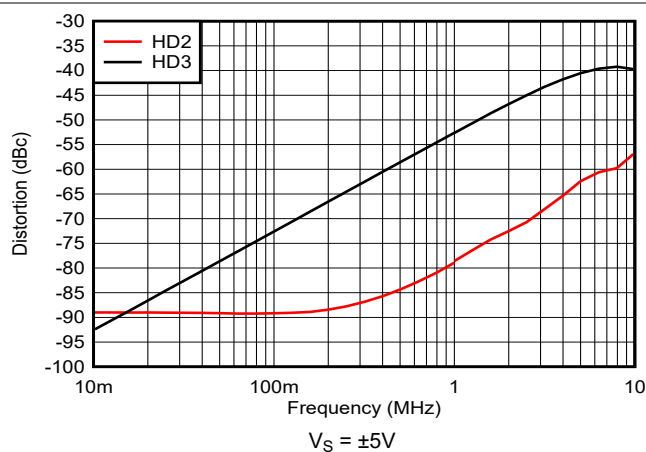


Figure 5-37. Harmonic Distortion vs Frequency

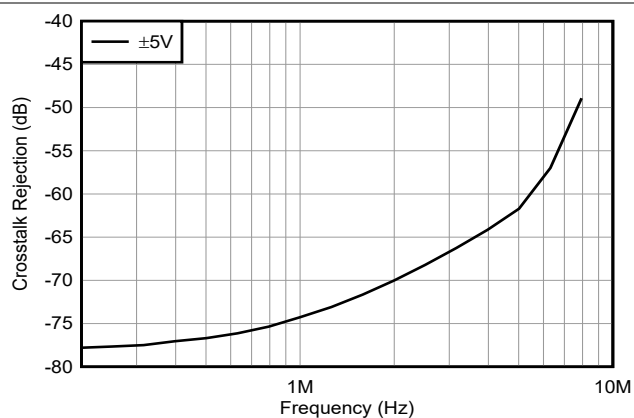


Figure 5-38. Crosstalk Rejection vs Frequency

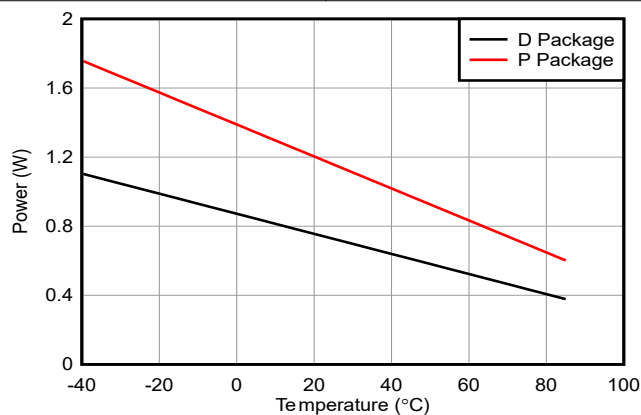


Figure 5-39. Maximum Power Dissipation vs Ambient Temperature

5.8 Typical Characteristics: P (PDIP, 8) Package

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

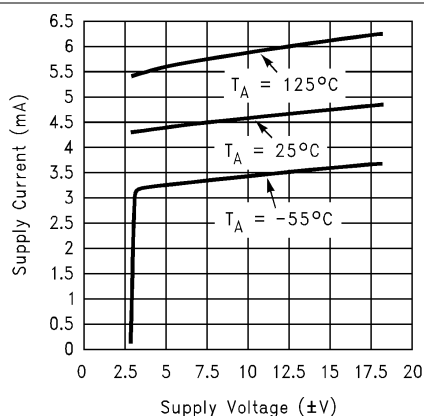


Figure 5-40. Supply Voltage vs. Supply Current

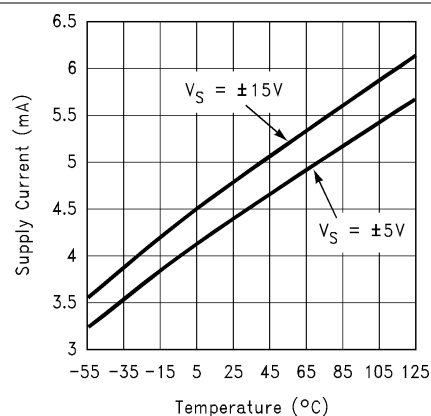


Figure 5-41. Supply Current vs. Temperature

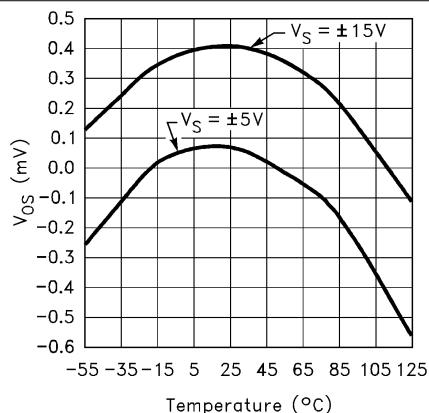


Figure 5-42. Input Offset Voltage vs. Temperature

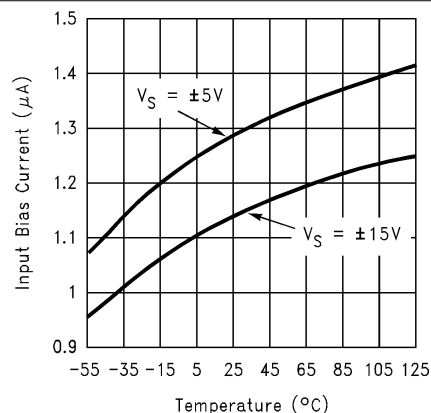


Figure 5-43. Input Bias Current vs. Temperature

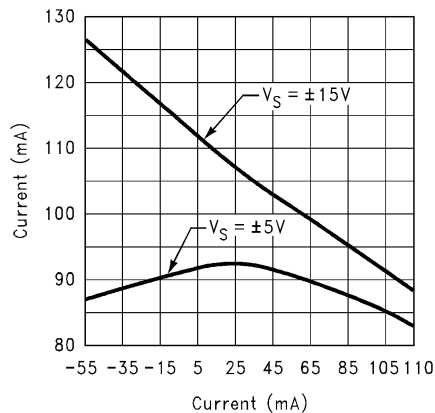


Figure 5-44. Short Circuit Current vs. Temperature (Sourcing)

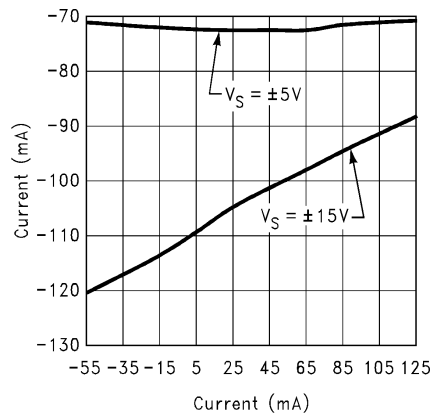


Figure 5-45. Short Circuit Current vs. Temperature (Sinking)

5.8 Typical Characteristics: P (PDIP, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

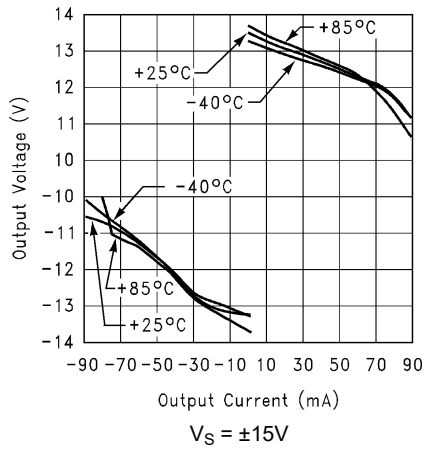


FIG 5-46. Output Voltage vs Output Current

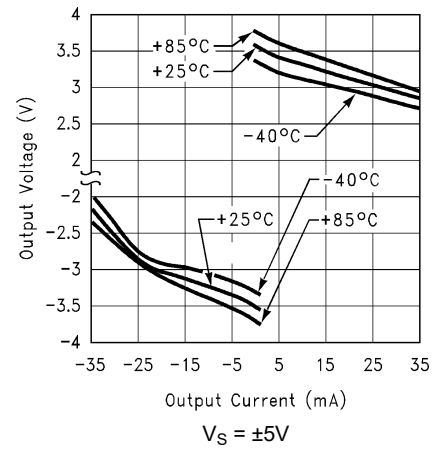


FIG 5-47. Output Voltage vs Output Current

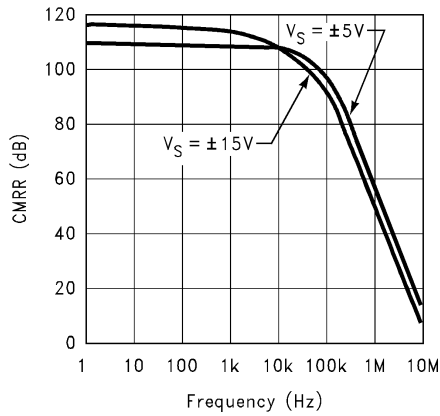


FIG 5-48. Common-Mode Rejection Ratio vs Frequency

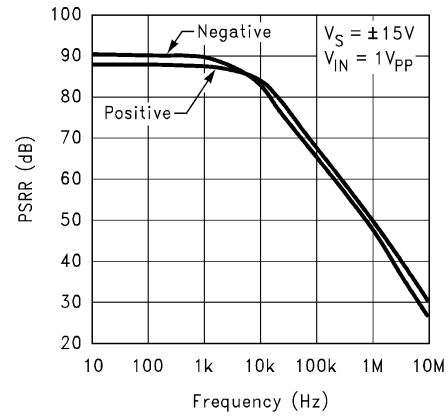


FIG 5-49. PSRR vs Frequency

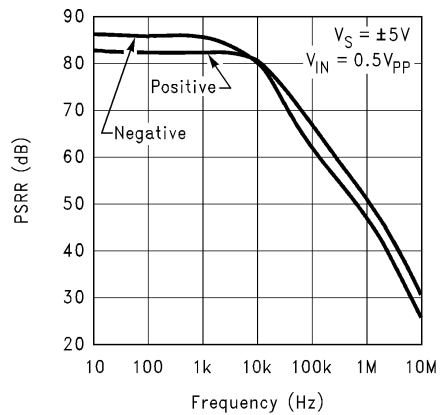


FIG 5-50. PSRR vs Frequency

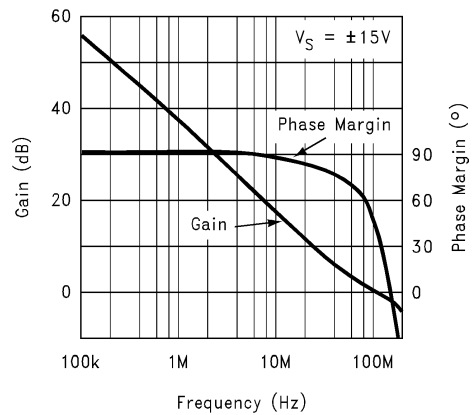


FIG 5-51. Open-Loop Frequency Response

5.8 Typical Characteristics: P (PDIP, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

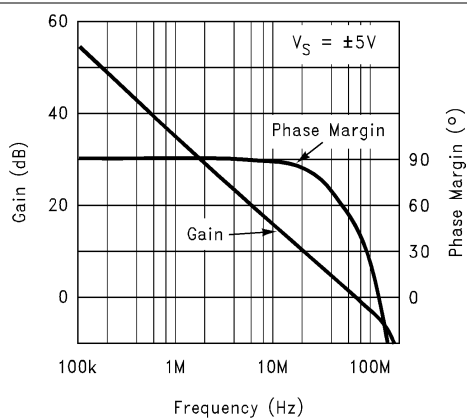


图 5-52. Open-Loop Frequency Response

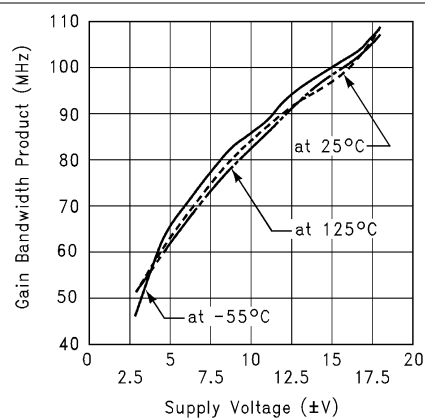


图 5-53. Gain-Bandwidth Product vs Supply Voltage at Different Temperature

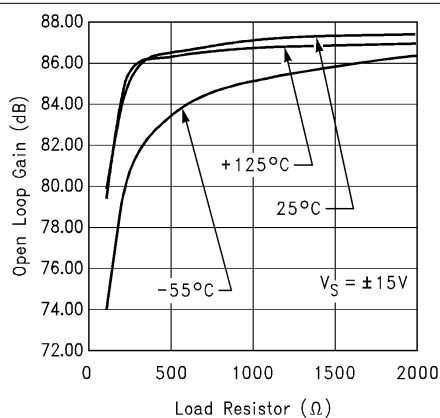


图 5-54. Large-Signal Voltage Gain vs Load

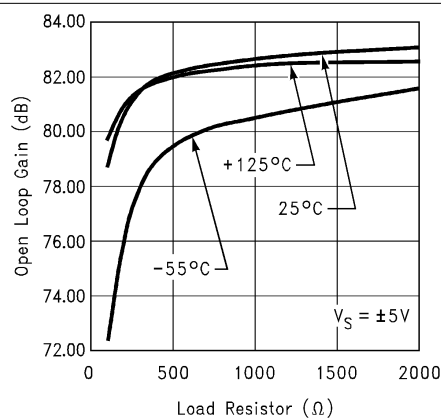


图 5-55. Large-Signal Voltage Gain vs Load

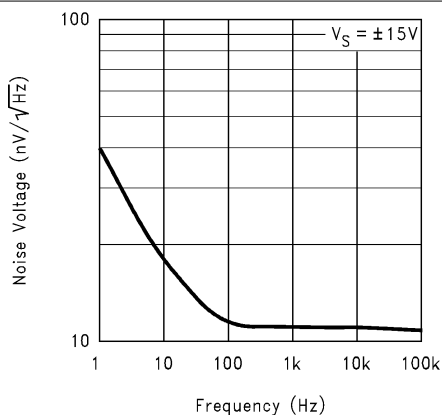


图 5-56. Input Voltage Noise vs Frequency

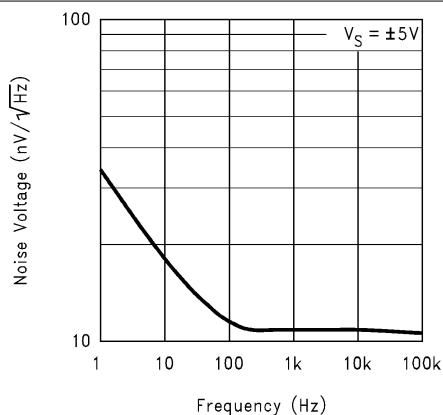
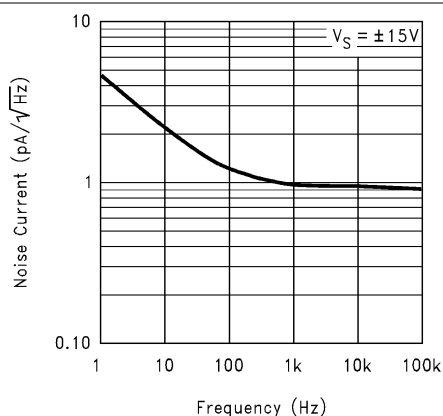


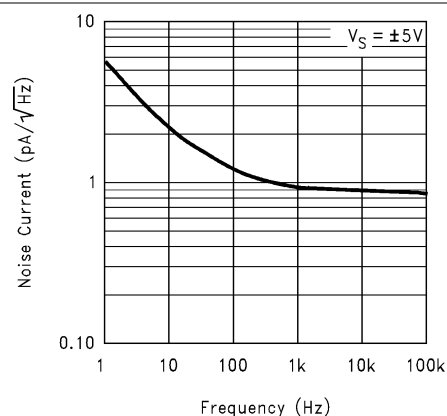
图 5-57. Input Voltage Noise vs Frequency

5.8 Typical Characteristics: P (PDIP, 8) Package (continued)

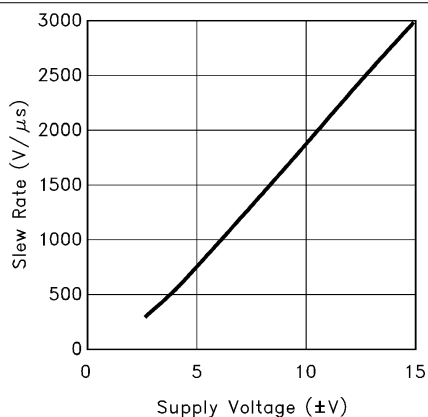
at $T_A = 25^\circ\text{C}$ (unless otherwise noted)



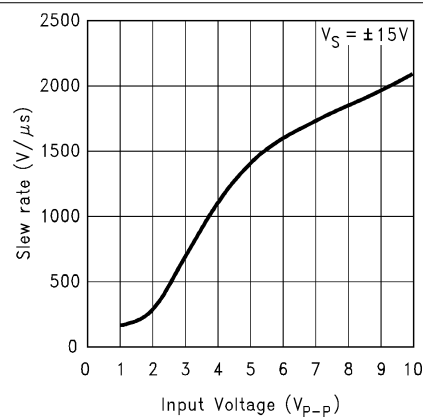
5-58. Input Current Noise vs Frequency



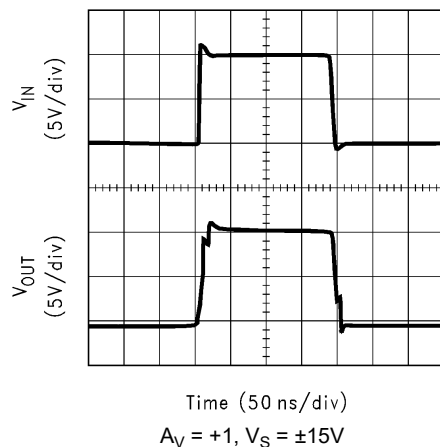
5-59. Input Current Noise vs Frequency



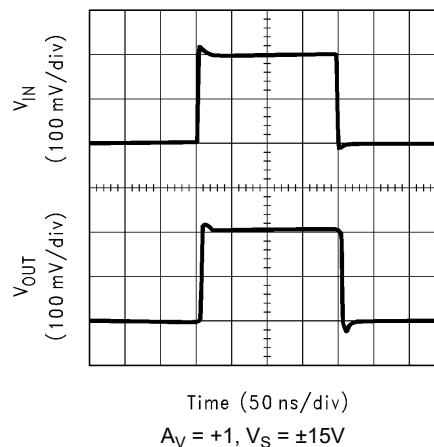
5-60. Slew Rate vs Supply Voltage



5-61. Slew Rate vs Input Voltage



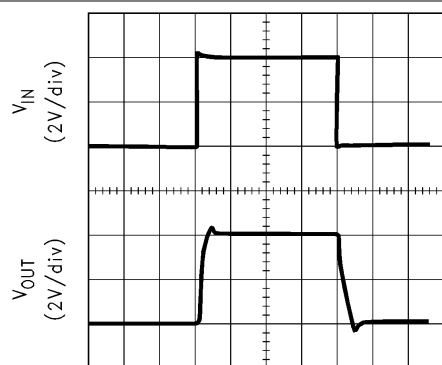
5-62. Large-Signal Pulse Response



5-63. Small-Signal Pulse Response

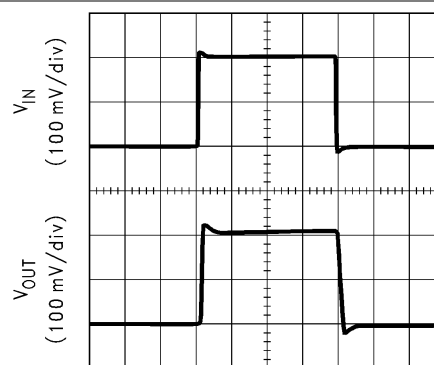
5.8 Typical Characteristics: P (PDIP, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)



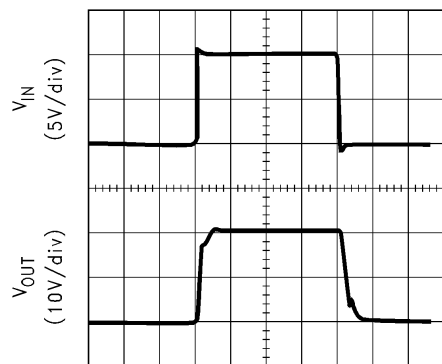
Time (50 ns/div)
 $A_V = +1$, $V_S = \pm 5\text{V}$

■ 5-64. Large-Signal Pulse Response



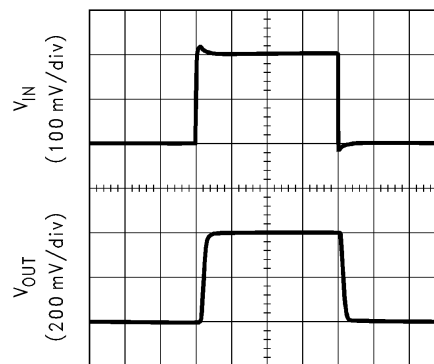
Time (50 ns/div)
 $A_V = +1$, $V_S = \pm 5\text{V}$

■ 5-65. Small-Signal Pulse Response



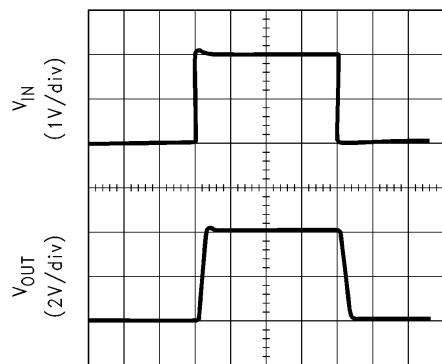
Time (50 ns/div)
 $A_V = +2$, $V_S = \pm 15\text{V}$

■ 5-66. Large-Signal Pulse Response



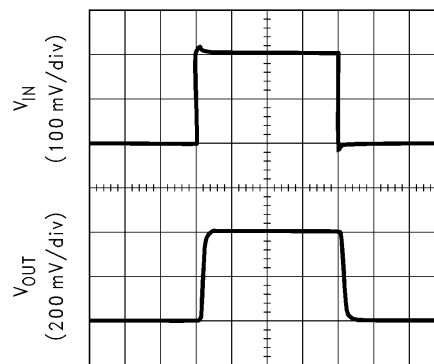
Time (50 ns/div)
 $A_V = +2$, $V_S = \pm 15\text{V}$

■ 5-67. Small-Signal Pulse Response



Time (50 ns/div)
 $A_V = +2$, $V_S = \pm 5\text{V}$

■ 5-68. Large-Signal Pulse Response



Time (50 ns/div)
 $A_V = +2$, $V_S = \pm 5\text{V}$

■ 5-69. Small-Signal Pulse Response

5.8 Typical Characteristics: P (PDIP, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

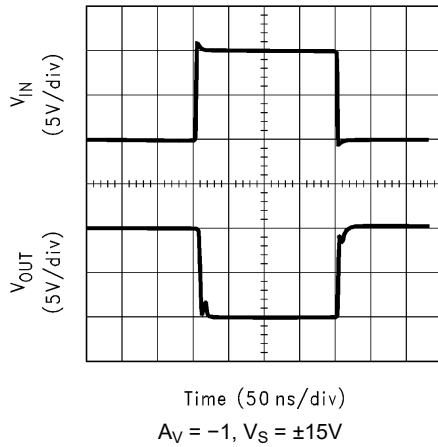


図 5-70. Large-Signal Pulse Response

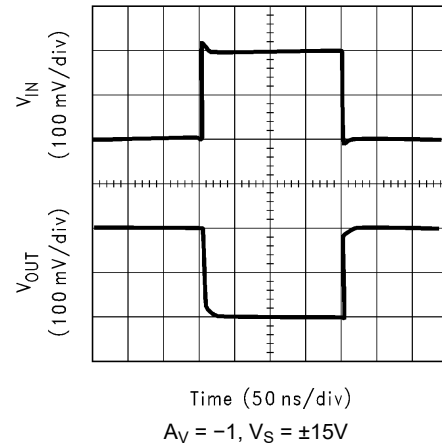


図 5-71. Small-Signal Pulse Response

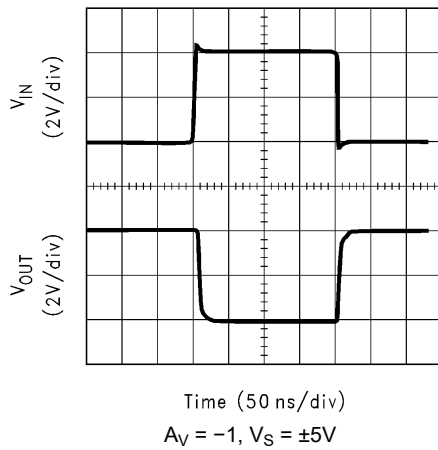


図 5-72. Large-Signal Pulse Response

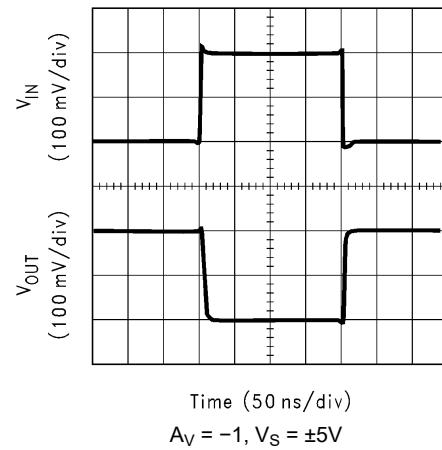


図 5-73. Small-Signal Pulse Response

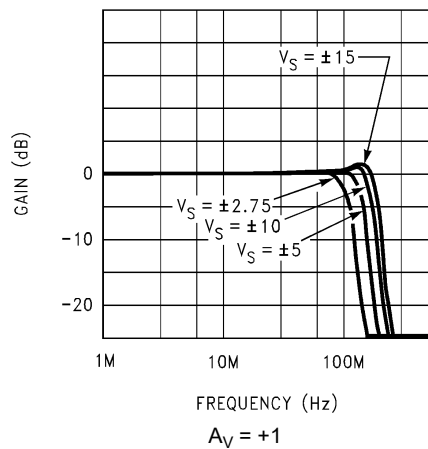


図 5-74. Closed-Loop Frequency Response vs Supply Voltage

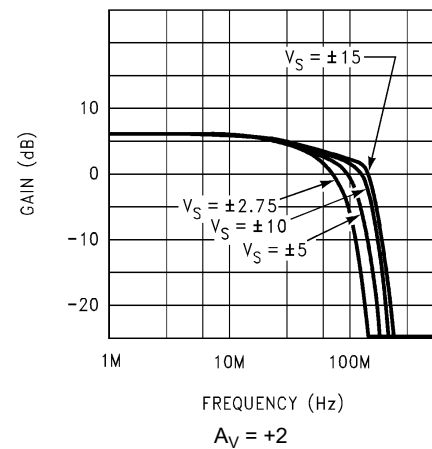


図 5-75. Closed-Loop Frequency Response vs Supply Voltage

5.8 Typical Characteristics: P (PDIP, 8) Package (continued)

at $T_A = 25^\circ\text{C}$ (unless otherwise noted)

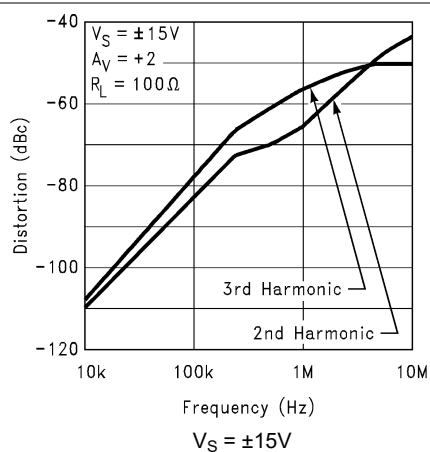


FIG 5-76. Harmonic Distortion vs Frequency

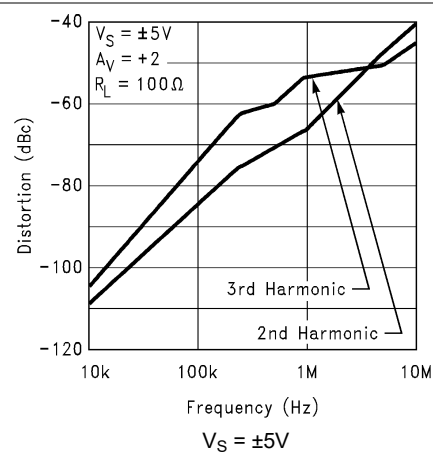


FIG 5-77. Harmonic Distortion vs Frequency

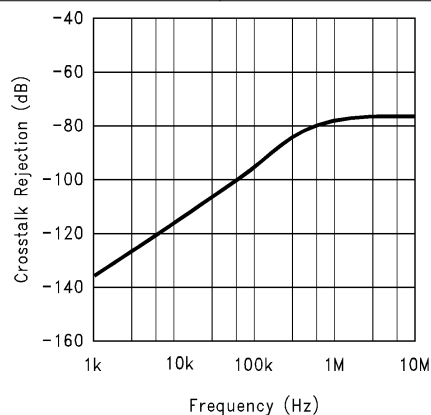


FIG 5-78. Crosstalk Rejection vs Frequency

7 Application and Implementation

注

以下のアプリケーション情報は、TI の製品仕様に含まれるものではなく、TI ではその正確性または完全性を保証いたしません。個々の目的に対する製品の適合性については、お客様の責任で判断していただくことになります。お客様は自身の設計実装を検証しテストすることで、システムの機能を確認する必要があります。

7.1 Application Information

7.1.1 Circuit Operation

The class AB input stage in LM6172 is fully symmetrical and has a similar slewing characteristic to the current feedback amplifiers. In the functional block diagram of [セクション 6.2](#), Q1 through Q4 form the equivalent of the current feedback input buffer, R_E the equivalent of the feedback resistor, and stage A buffers the inverting input. The triple-buffered output stage isolates the gain stage from the load to provide low output impedance.

7.1.2 Reduce Settling Time

The LM6172 has a very fast slew rate that causes overshoot and undershoot. To reduce settling time on LM6172, a 1k Ω resistor can be placed in series with the input signal to decrease slew rate. A feedback capacitor can also be used to reduce overshoot and undershoot. This feedback capacitor serves as a zero to increase the stability of the amplifier circuit. A 2pF feedback capacitor is recommended for initial evaluation. When the LM6172 is configured as a buffer, a feedback resistor of 1k Ω must be added in parallel to the feedback capacitor.

Another possible source of overshoot and undershoot comes from capacitive load at the output. See also [セクション 7.1.3](#).

7.1.3 Drive Capacitive Loads

Amplifiers that drive capacitive loads can oscillate or ring at the output. To eliminate oscillation or reduce ringing, place an isolation resistor as shown in [図 7-1](#). The combination of the isolation resistor and the load capacitor forms a pole to increase stability by adding more phase margin to the overall system. The desired performance depends on the value of the isolation resistor; the bigger the isolation resistor, the more damped (slow) the pulse response becomes. For the LM6172, a 50 Ω isolation resistor is recommended for initial evaluation.

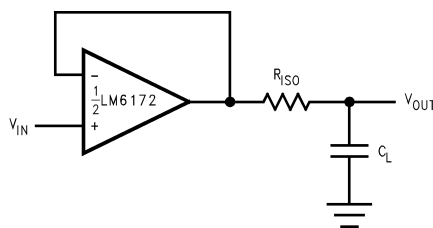


図 7-1. Isolation Resistor Used to Drive Capacitive Load

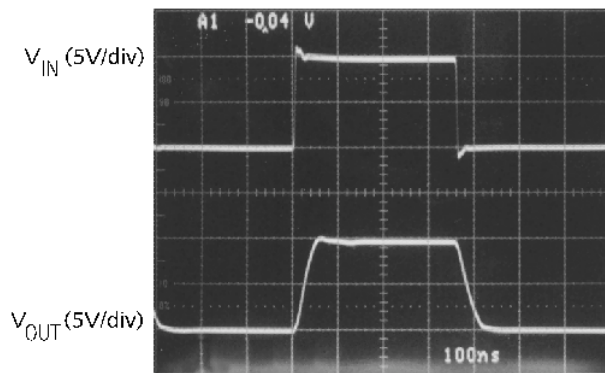


図 7-2. The LM6172 Driving a 510pF Load With a 30Ω Isolation Resistor

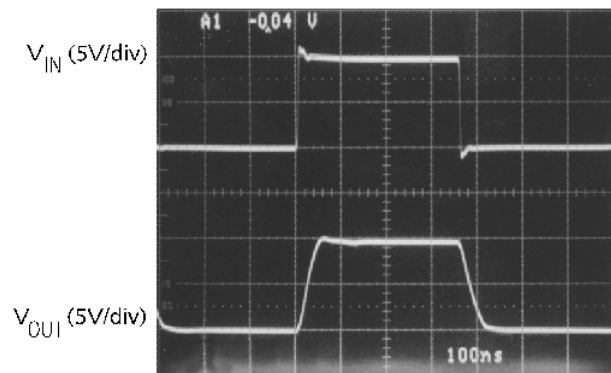


図 7-3. The LM6172 Driving a 220pF Load With a 50Ω Isolation Resistor

7.1.4 Compensation for Input Capacitance

The combination of an amplifier input capacitance with gain-setting resistors adds a pole that can cause peaking or oscillation. To solve this problem, a feedback capacitor with the following value can be used to cancel that pole:

$$C_F > (R_G \times C_{IN}) / R_F \quad (1)$$

For the LM6172, a feedback capacitor of 2pF is recommended. 図 7-4 illustrates the compensation circuit.

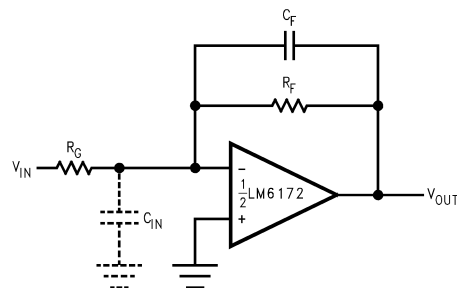


図 7-4. Compensating for Input Capacitance

7.1.5 Termination

In high-frequency applications, reflections occur if signals are not properly terminated. 図 7-5 shows a properly terminated signal while 図 7-6 shows an improperly terminated signal.

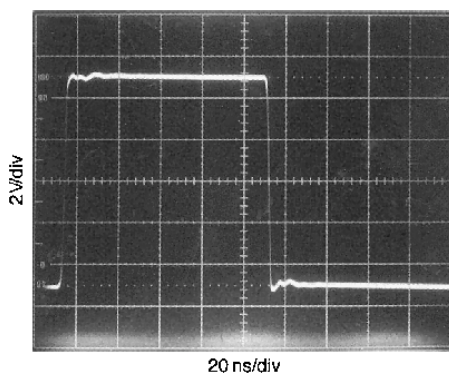


図 7-5. Properly Terminated Signal

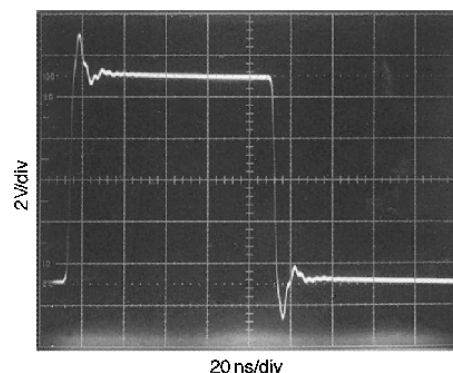


図 7-6. Improperly Terminated Signal

To minimize reflection, use coaxial cable with matching characteristic impedance to the signal source. Terminate the other end of the cable with the same value terminator or resistor. For commonly used cables, RG59 has a 75Ω characteristic impedance, and RG58 has a 50Ω characteristic impedance.

7.2 Typical Application

7.2.1 Application Circuits

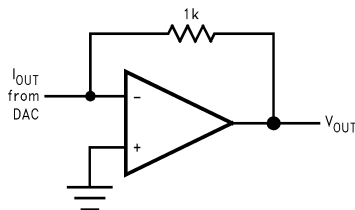


図 7-7. I-to-V Converters

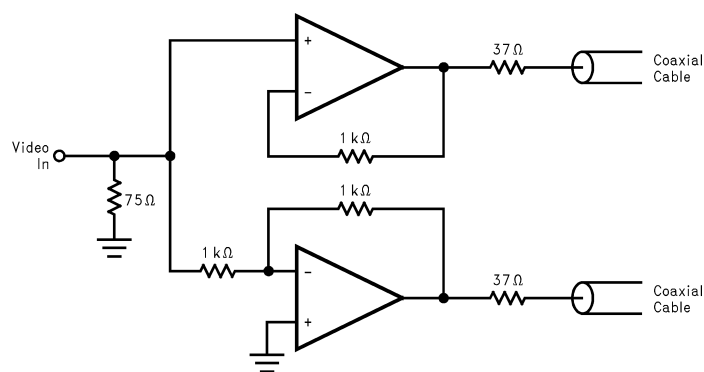


図 7-8. Differential Line Driver

7.3 Power Supply Recommendations

7.3.1 Power Supply Bypassing

Bypassing the power supply is necessary to maintain low power supply impedance across frequency. Bypass both positive and negative power supplies individually by placing 0.01μF ceramic capacitors directly to the power supply pins and 2.2μF tantalum capacitors close to the power-supply pins.

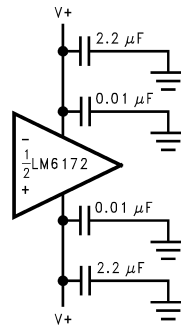


図 7-9. Power Supply Bypassing

7.3.2 Power Dissipation

The maximum power allowed to dissipate in a device is defined as:

$$P_D = (T_{J(max)} - T_A) / \theta_{JA} \quad (2)$$

where

- P_D is the power dissipation in a device
- $T_{J(max)}$ is the maximum junction temperature
- T_A is the ambient temperature
- θ_{JA} is the thermal resistance of a particular package

For example, for the LM6172 in a SOIC-8 package, the maximum power dissipation at 25°C ambient temperature is 726mW.

Thermal resistance, θ_{JA} , depends on parameters such as die size, package size, and package material. The smaller the die size and package, the higher the θ_{JA} . The 8-pin PDIP package has lower thermal resistance (108°C/W) than that of the 8-pin SOIC (172°C/W). Therefore, for higher dissipation capability, use an 8-pin PDIP.

The total power dissipated in a device can also be calculated as:

$$P_D = P_Q + P_L \quad (3)$$

where

- P_Q is quiescent power dissipated in a device with no load connected at the output.
- P_L is power dissipated in the device with a load connected at the output, not power dissipated by the load.

Furthermore,

- P_Q = supply current × total supply voltage with no load
- P_L = output current × (voltage difference between supply voltage and output voltage of the same supply)

For example, use 式 3 to solve the total power dissipated by the LM6172 with $V_S = \pm 15V$ and both channels swinging output voltage of 10V into 1kΩ:

$$\begin{aligned} &= 2[(2.3mA)(30V)] + 2[(10mA)(15V - 10V)] \\ &= 138mW + 100mW \\ &= 238mW \end{aligned}$$

7.4 Layout

7.4.1 Layout Guidelines

7.4.1.1 Printed Circuit Boards and High-Speed Op Amps

There are many things to consider when designing printed circuit boards (PCBs) for high-speed op amps. Without proper caution, excessive ringing, oscillation and other degraded ac performance in high-speed circuits can occur. As a rule, use short and wide the signal traces to provide low inductance and low impedance paths. Ground any unused board space to reduce stray signal pickup. Also ground critical components at a common point to eliminate voltage drop. Sockets add capacitance to the board and can affect frequency performance. Best practice is to solder the amplifier directly into the PCB without using a socket.

7.4.1.2 Using Probes

Active (FET) probes are an excellent choice for taking high-frequency measurements because these probes have wide bandwidth, high input impedance, and low input capacitance. However, the probe ground leads provide a long ground loop that produces errors in measurement. Instead, ground the probes directly by removing the ground leads and probe jackets and using scope probe jacks.

7.4.1.3 Components Selection and Feedback Resistor

In high-speed applications, keep all component leads short because wires are inductive at high frequency. For discrete components, choose carbon composition-type resistors and mica-type capacitors. Surface-mount components are preferred over discrete components for minimum inductive effect.

Large values of feedback resistors can couple with parasitic capacitance and cause undesirable effects such as ringing or oscillation in high-speed amplifiers. For the LM6172, a feedback resistor less than 1k Ω gives optimized performance.

8 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

8.1 ドキュメントの更新通知を受け取る方法

ドキュメントの更新についての通知を受け取るには、www.tij.co.jp のデバイス製品フォルダを開いてください。[通知] をクリックして登録すると、変更されたすべての製品情報に関するダイジェストを毎週受け取ることができます。変更の詳細については、改訂されたドキュメントに含まれている改訂履歴をご覧ください。

8.2 サポート・リソース

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8.5 用語集

[テキサス・インスツルメンツ用語集](#) この用語集には、用語や略語の一覧および定義が記載されています。

9 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision D (March 2013) to Revision E (December 2024)	Page
• ドキュメント全体にわたって表、図、相互参照の採番方法を更新.....	1
• 「パッケージ情報」表、「ピン構成および機能」、「仕様」、「ESD 定格」、「推奨動作条件」、「熱に関する情報」、「詳細説明」、「概要」、「機能ブロック図」、「機能説明」、「デバイスの機能モード」、「アプリケーションと実装」、「代表的なアプリケーション」、「電源に関する推奨事項」、「レイアウト」、「レイアウトのガイドライン」、「レイアウト例」、「デバイスおよびドキュメントのサポート」、「メカニカル、パッケージ、および注文情報」セクションを追加	1
• Changed pin names and updated pinout diagram to reflect new naming convention.....	3
• Updated <i>Thermal Information</i> for the D (SOIC-8) and P (PDIP-8) packages.....	4
• Moved <i>DC and AC Electrical Characteristics</i> into one table for both $\pm 15V$ and $\pm 5V$ specifications.....	5
• Changed output short-circuit current for D package.....	5
• Updated unity-gain bandwidth from 100MHz to 80MHz for D package.....	5
• Updated second harmonic distortion for D package.....	5
• Updated third harmonic distortion for D package.....	5
• Changed output short-circuit current for D package.....	7
• Updated –3dB frequency for D package.....	7
• Updated phase margin for D package.....	7
• Updated second harmonic distortion for D package.....	7

• Updated third harmonic distortion for D package.....	7
• Deleted <i>Maximum Power Dissipation vs Ambient Temperature</i>	16
• Changed thermal values in <i>Power Dissipation</i> to match <i>Thermal Information</i> table.....	27

Changes from Revision C (March 2013) to Revision D (March 2013)	Page
• Deleted ESD information and footnote from <i>Absolute Maximum Ratings</i> and moved to <i>ESD Ratings</i>	4
• Deleted footnote from <i>Recommended Operating Conditions</i>	4
• Changed layout of National Data Sheet to TI format.....	26

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
LM6172IM/NOPB	Obsolete	Production	SOIC (D) 8	-	-	Call TI	Call TI	-40 to 85	LM61 72IM
LM6172IMX/NOPB	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU SN	Level-2-260C-1 YEAR	-40 to 85	LM61 72IM
LM6172IMX/NOPB.A	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LM61 72IM
LM6172IMX/NOPB.B	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LM61 72IM
LM6172IN/NOPB	Active	Production	PDIP (P) 8	40 TUBE	Yes	NIPDAU	Level-1-NA-UNLIM	-40 to 85	LM6172IN
LM6172IN/NOPB.A	Active	Production	PDIP (P) 8	40 TUBE	Yes	NIPDAU	Level-1-NA-UNLIM	-40 to 85	LM6172IN
LM6172IN/NOPB.B	Active	Production	PDIP (P) 8	40 TUBE	Yes	NIPDAU	Level-1-NA-UNLIM	-40 to 85	LM6172IN

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM6172IMX/NOPB	SOIC	D	8	2500	330.0	12.4	6.5	5.4	2.0	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM6172IMX/NOPB	SOIC	D	8	2500	367.0	367.0	35.0

TUBE


*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
LM6172IN/NOPB	P	PDIP	8	40	502	14	11938	4.32
LM6172IN/NOPB.A	P	PDIP	8	40	502	14	11938	4.32
LM6172IN/NOPB.B	P	PDIP	8	40	502	14	11938	4.32



PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE:8X

4214825/C 02/2019

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

P (R-PDIP-T8)

PLASTIC DUAL-IN-LINE PACKAGE



- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. Falls within JEDEC MS-001 variation BA.

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